



ICANS 28

28th International conference
on Amorphous
and Nanocrystalline
Semiconductors

4-9 August 2019

École polytechnique - Palaiseau - France

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Monday, 5 August 2019

18:20-20:20 Poster Session

Materials

<p>Effect of Sn ion implantation on the structural and optical properties of amorphous Ge₂Sb₂Te₅ thin films P. Lazarenko, S. Kozyukhin, B. Eszter, A. Sitnikov, V. Glukhenkaya, F. Tamás, D. Seleznev, E. Kirilenko, A. Dedkova, A. Sherchenkov</p>	<p>Mo.Mat.P1</p>
<p>Charge Exchange at Valence Alternation Pairs in Amorphous Selenium During Transient Optical Excitation and Photocurrent Decay J. Jacobs, S. Kasap, G. Belev, R. J. Curry</p>	<p>Mo.Mat.P2</p>
<p>Optical properties of amorphous film composites TiO₂<Ag>and C-TiO₂<Ag> Y. Mukhametkarimov, O. Prikhodko, K. Dauitkhan, S. Mikhailova, U. Doseke, S. Maksimova, K. Tauassarov</p>	<p>Mo.Mat.P3</p>
<p>Switching effect in thin Ge₂Sb₂Te₅ films modified by silver impurity N. Almassov, S. Dyussebayev, A. Serikkanov, A. Kadirov, N. Guseinov, Z. Tolepov</p>	<p>Mo.Mat.P4</p>
<p>Reorganization of Interface Porosity of Crystalline Silicon Grown by Low Temperature Plasma Epitaxy J. E. Hong, J. Ho Oh, K. H. Kim</p>	<p>Mo.Mat.P5</p>
<p>Grain Agglomeration in Low Temperature (250°C) Wet Annealed In-Zn-O Films for use in Solution Processed Thin-film Transistors M. P. A. Jallorina, J. P. S. Bermundo, M. N. Fujii, Y. Ishikawa, Y. Uraoka</p>	<p>Mo.Mat.P6</p>
<p>The Lateral Growth of GeSn Wires on Patterned Si Substrate Y. Zhao, X. Zhang, B. Cheng, S. Feng, Y. Wang, C. Li</p>	<p>Mo.Mat.P7</p>
<p>Synthesis of Poly-Si Film by Al-Catalyzed Conversion of Silicon Oxide Films J. H. Yoon</p>	<p>Mo.Mat.P8</p>
<p>Optical properties of nanoscale Ge₂Sb₂Te₅ films modified with Ag and Bi O. Prikhodko, K. Turmanova, Z. Tolepov, A. Zhakypov, A. Sazonov, S. Maksimova, G. Ismailova, S. Mikhailova</p>	<p>Mo.Mat.P9</p>
<p>High-conductivity P-doped hydrogenated amorphous silicon-germanium (a-SixGe1-x:H) thin-films for thermoelectric C. R. Ascencio-Hurtado, A. Torres, R. Ambrosio, M. Moreno, I. E. Zapata-De Santiago, A. Itzmóyotl</p>	<p>Mo.Mat.P10</p>

Characterization

<p>Passivated Selective Contact Structure Characterization by C-AFM and KPFM of the Conduction by Pinholes C. Marchat, A. Morisset, J. Alvarez, R. Cabal, M. E. Gueunier-Farret, J. P. Kleider</p>	<p>Mo.Ch.P1</p>
<p>Nanoscale Study of the Hole-selective Passivating Contacts for High-Efficiency Silicon Solar Cells Using C-AFM Tomography M. Hývl, G. Nogay, F. J. Haug, P. Loper, A. Ingenito, M. Ledinský, C. Ballif, A. Fejfar</p>	<p>Mo.Ch.P2</p>
<p>Electroformed Silicon Nitride-Based Light Emitting Memory Device Investigated by SEM, EDX and Real-Time Optical Microscopy Analyses M. Anutgan, T. Anutgan, I. Atilgan</p>	<p>Mo.Ch.P3</p>
<p>Investigation on Luminescent Quantum Efficiencies, Luminescent Stabilities and Ultrafast Radiative Recombination Processes in a-SiNxOy Systems P. Zhang, L. Zhang, F. Lv, R. Cheng, F. Liu, J. Zhang, Y. Li</p>	<p>Mo.Ch.P4</p>
<p>Alternating Current Implementations of the Moving Photocarrier Grating Technique L. Kopprio, F. Ventosinos, C. Longeaud, J. Schmidt</p>	<p>Mo.Ch.P5</p>
<p>Photoluminescence Decay Mapping for the Inhomogeneities Imaging of Passivated Silicon D. Kudryashov, A. Gudovskikh, I. Morozov</p>	<p>Mo.Ch.P6</p>
<p>Growth Kinetics of H₂ Plasma Subjected a-Si:H Films: AFM Surface Morphology Studies V. Kanneboina, R. Madaka, P. Agarwal</p>	<p>Mo.Ch.P7</p>
<p>The Interpretation of Infrared Spectra of Si-H and/or Si-H₂ Groups on Si(111), Si(110) and Si(100) Surfaces J. Šebera, V. Sychrovský, J. Zemen, V. Jirásek, J. Holovský</p>	<p>Mo.Ch.P8</p>
<p>Optical and Structural Properties of Amorphous Silicon-Carbon alloys thin films S. Nemmour, F. Kail, L. Chahed, P. Roca i Cabarrocas</p>	<p>Mo.Ch.P9</p>
<p>a-SixGe1-x:H Thermoelectric Thin Film Schottky Diodes: Characterization and Applications I. E. Zapata-De Santiago, A. Torres, C. R. Ascencio-Hurtado, C. Reyes, M. T. Sanz, A. Itzmóyotl</p>	<p>Mo.Ch.P10</p>
<p>Investigation of ZnO/BST Interface for Thin Film Transistor Applications K. Kandpal, N. Gupta, J. Singh, C. Shekhar</p>	<p>Mo.Ch.P11</p>

Optical properties of amorphous film composites $\text{TiO}_2\langle\text{Ag}\rangle$ and $\text{C-TiO}_2\langle\text{Ag}\rangle$

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Currently, the amorphous semiconductor nanocomposite materials based on titanium dioxide and silver nanoparticles ($\text{TiO}_2\langle\text{Ag}\rangle$) have a special interest [1, 2]. This is due to the specific features of the composite components. For example, TiO_2 films have the highest refractive index in the visible region of the spectrum among all similar materials used as a matrix. In addition, TiO_2 films have high photoactivity in the UV radiation range, which makes it possible to use them in optoelectronics, solar energy and etc. [3].

In this paper we study the optical plasmon resonance in film composites based on titanium dioxide TiO_2 and C-TiO_2 matrices and silver nanoparticles ($\text{TiO}_2\langle\text{Ag}\rangle$ and $\text{C-TiO}_2\langle\text{Ag}\rangle$, respectively). The film composites were obtained by ion-plasma RF co-sputtering of titanium dioxide and silver as well as titanium dioxide, silver and graphite combined targets. It is shown that $\text{TiO}_2\langle\text{Ag}\rangle$ film nanocomposites are characterized by an amorphous TiO_2 matrix containing isolated ~ 2 nm sized silver nanoparticles. It is established that the TiO_2 matrix is a wide-gap semiconductor with conductivity at room temperature $\sigma = 6.6 \cdot 10^{-10} \text{ Ohm}^{-1} \cdot \text{cm}^{-1}$ and the optical band gap $E_g = 3.2$ eV.

Fig. 1 shows the optical density spectra of the $\text{TiO}_2\langle\text{Ag}\rangle$ and $\text{C-TiO}_2\langle\text{Ag}\rangle$ nanocomposites. It follows from the **fig.1** that resonance absorption in $\text{TiO}_2\langle\text{Ag}\rangle$ film composites is characterized by a wide asymmetrical resonance peak with maximum approximately at 500 nm. Modification of $\text{TiO}_2\langle\text{Ag}\rangle$ nanocomposite with carbon atoms leads to the increase in the intensity of resonance absorption peak and to the shift of the maximum to the short-wavelength region of the spectrum, from 500 nm to 484 nm.

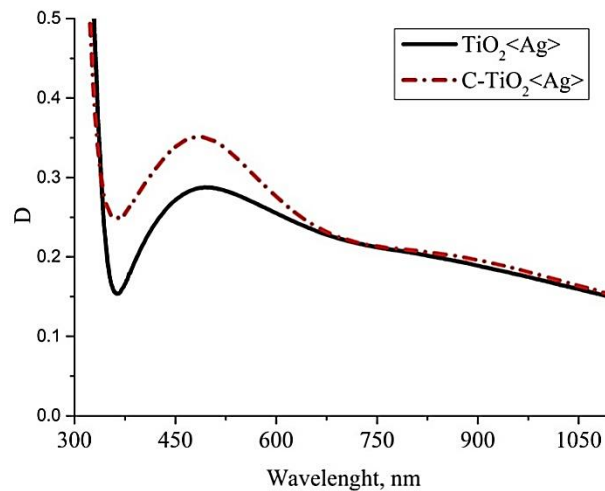


Fig. 1 Optical density of the $\text{TiO}_2\langle\text{Ag}\rangle$ and $\text{C-TiO}_2\langle\text{Ag}\rangle$ films

The differences in the optical resonance absorption spectra for $\text{TiO}_2\langle\text{Ag}\rangle$ and $\text{C-TiO}_2\langle\text{Ag}\rangle$ composites apparently are due to an additional clusterization of silver nanoparticles in the matrix $\text{C-TiO}_2\langle\text{Ag}\rangle$ owing to carbon atoms presence.

Keywords: titanium dioxide, amorphous carbon, film composites, plasmon resonance

References

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- [2] Oleg Prikhodko, Svetlana Mikhailova, Yerzhan Mukhametkarimov et al, *Optical properties of a-C:H thin films modified by Ti and Ag*, Proceedings of SPIE, **9929**, p. 99291G-1 – 6 (2016)
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Acknowledgments

This work was supported by the AP05132897 grant of the Ministry of Education and Science of Kazakhstan